In re Patent Application of : Docket No.: YOR920030402US1

Chandramouli Visweswariah : Group Art Unit:

Serial No.: To be Assigned : Examiner:

Filed: Herewith : Date: September 19, 2003

For: SYSTEM AND METHOD FOR PROBABILISTIC CRITICALITY

PREDICTION OF DIGITAL CIRCUITS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents Box Patent Application Washington, D.C. 20231

Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicants' attorney wishes to bring to the attention of the Patent and Trademark Office the document listed on the accompanying form PTO-1449. A copy of the listed document is enclosed. It is respectfully requested that the Examiner consider the cited document and return an initialed copy of the form PTO-1449.

The filing of this Information Disclosure Statement shall not be construed as a representation that a search has been made, or as an admission that the information cited is considered to be material to patentability, or as a representation that no other material information exists.

Respectfully submitted,

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Express Mail: EV355345809US Date of Deposit: September 19, 2003 ATTY. DOCKET NO.: SERIAL NO .: FORM PTO-1449 (Modified) CONFIRMATION NO. YOR920030402US1 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION APPLICANT: Chandramouli Visweswariah **DISCLOSURE STATEMENT** (Use several sheets if necessary) FILING DATE: HEREWITH GROUP: REFERENCE DESIGNATION U.S. PATENT DOCUMENTS DOCUMENT **EXAMINER** FILING DATE **INITIALS** NUMBER DATE **SUBCLASS** NAME **CLASS** (IF APPRO.) AA ΑB AC AD ΑE ΑF FOREIGN PATENT DOCUMENTS DOCUMENT **TRANSLATION** NUMBER DATE COUNTRY SUBCLASS **CLASS** YES NO OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.) Statistical Timing of Parametric Yield Prediction of Digital Integrated Circuits, by J.A.G. Jess, K. Kalafala, S.R. ΑI Naidu, R.H.J.M. Otten, C. Visweswariah, pp. 932-937, Design Automation Conference 2003 Fast Statistical Timing Analysis By Probabilistic Event Propagation, by Jing-Jia Liou, Kwang-Ting Cheng, Sandip Kundu, and Angela Krstic, pp. 661-666, Design Automation Conference 2001 Explicit Computation of Performance as a Function of Process Variation by Lou Scheffer, TAU '02, pp. 1-8 Timing Yield Estimation from Static Timing Analysis, by Anne Gattiker, Sani Nassif, Rashmi Dinakar, and Chris Long, pp. 437-442, International Symposium on Quality Electronic Design, 2001. DATE CONSIDERED **EXAMINER** EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449 (Modified) LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	ATTY. DOCKET NO. : YO	SERIAL NO.: CONFIRMATION NO.
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